



F100352

Low Power 8-Bit Buffer with Cut-Off Drivers

General Description

The F100352 contains an 8-bit buffer, individual inputs (Dn), outputs (Qn), and a data output enable pin (\overline{OEN}). A Q output follows its D input when the \overline{OEN} pin is LOW. A HIGH on \overline{OEN} holds the outputs in a cut-off state. The cut-off state is designed to be more negative than a normal ECL LOW level. This allows the output emitter-followers to turn off when the termination supply is $-2.0V$, presenting a high impedance to the data bus. This high impedance reduces termination power and prevents loss of low state noise margin when several loads share the bus.

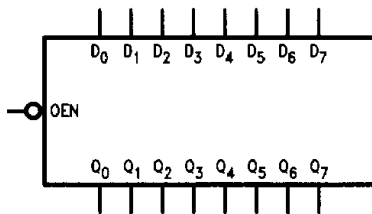
The F100352 outputs are designed to drive a doubly terminated 50Ω transmission line (25Ω load impedance). All inputs have $50\text{ k}\Omega$ pull-down resistors.

Features

- Cut-off drivers
- Drives 25Ω load
- Low power operation
- 2000V ESD protection
- Voltage compensated operating range = $-4.2V$ to $-5.7V$

Ordering Code: See Section 8

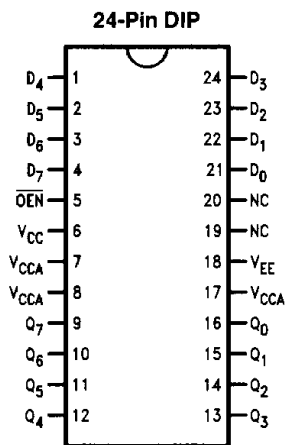
Logic Symbol



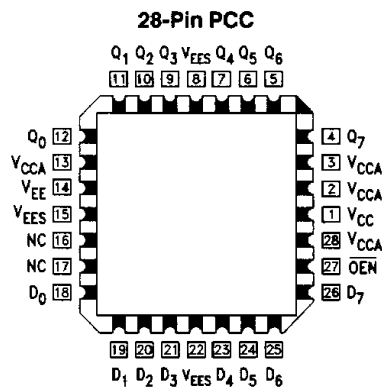
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Pin Names	Description
D ₀ -D ₇	Data Inputs
\overline{OEN}	Output Enable Input
Q ₀ -Q ₇	Data Outputs
NC	No Connect

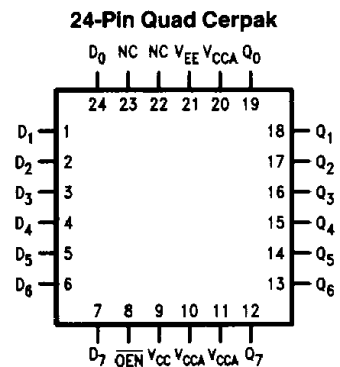
Connection Diagrams



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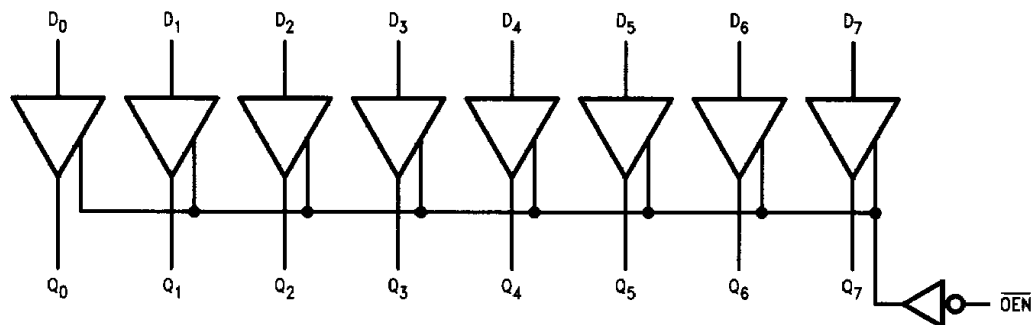


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Logic Diagram



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Truth Table

Inputs		Outputs
D_n	\overline{OEN}	Q_n
L	L	L
H	L	H
X	H	Cutoff

H = HIGH Voltage Level
 L = LOW Voltage Level
 Cutoff = Lower-than-LOW State
 X = Don't Care

Absolute Maximum Ratings

Above which the useful life may be impaired (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Storage Temperature (T _{STG})	-65°C to +150°C
Maximum Junction Temperature (T _J)	
Ceramic	+175°C
Plastic	+150°C
V _{EE} Pin Potential to Ground Pin	-7.0V to +0.5V
Input Voltage (DC)	V _{EE} to +0.5V
Output Current (DC Output HIGH)	-100 mA
ESD (Note 2)	≥2000V

Commercial Version

DC Electrical Characteristics

V_{EE} = -4.2V to -5.7V, V_{CC} = V_{CCA} = GND, T_C = 0°C to +85°C (Note 3)

Symbol	Parameter	Min	Typ	Max	Units	Conditions
V _{OH}	Output HIGH Voltage	-1025	-955	-870	mV	V _{IN} = V _{IH} (Max) or V _{IL} (Min) Loading with 25Ω to -2.0V
V _{OL}	Output LOW Voltage	-1830	-1705	-1620		
V _{OH} C	Output HIGH Voltage	-1035			mV	V _{IN} = V _{IH} (Min) or V _{IL} (Max) Loading with 25Ω to -2.0V
V _{OL} C	Output LOW Voltage			-1610		
V _{OL} Z	Cut-Off LOW Voltage			-1950	mV	V _{IN} = V _{IH} (Min) or V _{IL} (Max) OEN = HIGH
V _{IH}	Input HIGH Voltage	-1165		-870	mV	Guaranteed HIGH Signal for All Inputs
V _{IL}	Input LOW Voltage	-1830		-1475	mV	Guaranteed LOW Signal for All Inputs
I _{IL}	Input LOW Current	0.50			μA	V _{IN} = V _{IL} (Min)
I _{IH}	Input HIGH Current			240	μA	V _{IN} = V _{IH} (Max)
I _{EE}	Power Supply Current	-138 -143		-70 -70	mA	Inputs Open V _{EE} = -4.2V to -4.8V V _{EE} = -4.2V to -5.7V

Note 1: Absolute maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: ESD testing conforms to MIL-STD-883, Method 3015.

Note 3: The specified limits represent the "worst case" value for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guardbanding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions.

Commercial Version (Continued)**Ceramic Dual-In-Line Package AC Electrical Characteristics** $V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
t_{PLH} t_{PHL}	Propagation Delay Dn to Output	0.70	2.00	0.70	2.00	0.70	2.20	ns	Figures 1, 2 (Note 1)
t_{PZH} t_{PHZ}	Propagation Delay OEN to Output	1.60	4.20	1.60	4.20	1.60	4.20	ns	Figures 1, 2 (Note 1)
t_{TLH} t_{THL}	Transition Time 20% to 80%, 80% to 20%	0.45	2.00	0.45	2.00	0.45	2.00	ns	Figures 1, 2

Note 1: The propagation delay specified is for single output switching. Delays may vary up to 300 ps with multiple outputs switching.

PCC and Cerpak AC Electrical Characteristics $V_{EE} = 4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
t_{PLH} t_{PHL}	Propagation Delay Dn to Output	0.70	1.80	0.70	1.80	0.70	2.00	ns	Figures 1, 2 (Note 2)
t_{PZH} t_{PHZ}	Propagation Delay OEN to Output	1.60	4.00	1.60	4.00	1.60	4.00	ns	Figures 1, 2 (Note 2)
t_{TLH} t_{THL}	Transition Time 20% to 80%, 80% to 20%	0.45	1.90	0.45	1.90	0.45	1.90	ns	Figures 1, 2
$t_{S,G-G}$	Skew, Gate to Gate	TBD		TBD		TBD		ps	PCC Only (Note 1)

Note 1: Gate to gate skew is defined as the difference in propagation delays between each of the outputs.

Note 2: The propagation delay specified is for single output switching. Delays may vary up to 300 ps with multiple outputs switching.

Military Version—Preliminary**DC Electrical Characteristics** $V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$, $T_C = -55^\circ C$ to $+125^\circ C$

Symbol	Parameter	Min	Max	Units	T_C	Conditions	Notes	
V_{OH}	Output HIGH Voltage	-1025	-870	mV	$0^\circ C$ to $+125^\circ C$	$V_{IN} = V_{IH(Max)}$ or $V_{IL(Min)}$	Loading with 25Ω to $-2.0V$	1, 2, 3
		-1085	-870	mV	$-55^\circ C$			
V_{OL}	Output LOW Voltage	-1830	-1620	mV	$0^\circ C$ to $+125^\circ C$	$V_{IN} = V_{IH(Min)}$ or $V_{IL(Max)}$	Loading with 25Ω to $-2.0V$	1, 2, 3
		-1830	-1555	mV	$-55^\circ C$			
V_{OHC}	Output HIGH Voltage	-1035		mV	$0^\circ C$ to $+125^\circ C$	$V_{IN} = V_{IH(Min)}$ or $V_{IL(Max)}$	Loading with 25Ω to $-2.0V$	1, 2, 3
		-1085		mV	$-55^\circ C$			
V_{OLC}	Output LOW Voltage		-1610	mV	$0^\circ C$ to $+125^\circ C$	$V_{IN} = V_{IH(Min)}$ or $V_{IL(Max)}$	Loading with 25Ω to $-2.0V$	1, 2, 3
			-1555	mV	$-55^\circ C$			
V_{OLZ}	Cut-Off LOW Voltage		-1950	mV	$0^\circ C$ to $+125^\circ C$	$V_{IN} = V_{IH(Min)}$, or $V_{IL(Max)}$	$\overline{OEN} = HIGH$	1, 2, 3
			-1850		$-55^\circ C$			
V_{IH}	Input HIGH Voltage	-1165	-870	mV	$-55^\circ C$ to $+125^\circ C$	Guaranteed HIGH signal for All inputs	1, 2, 3, 4	
V_{IL}	Input LOW Voltage	-1830	-1475	mV	$-55^\circ C$ to $+125^\circ C$	Guaranteed LOW signal for All inputs	1, 2, 3, 4	
I_{IL}	Input LOW Current	0.50		μA	$-55^\circ C$ to $+125^\circ C$	$V_{EE} = 4.2V$ $V_{IN} = V_{IL(Min)}$	1, 2, 3	
I_{IH}	Input HIGH Current		240	μA	$0^\circ C$ to $+125^\circ C$	$V_{EE} = -5.7V$ $V_{IN} = V_{IH(Max)}$	1, 2, 3	
			340	μA	$-55^\circ C$			
I_{EE}	Power Supply Current	-145 -150	-55	mA	$-55^\circ C$ to $+125^\circ C$	Inputs Open $V_{EE} = -4.2V$ to $-4.8V$ $V_{EE} = -4.2V$ to $-5.7V$	1, 2, 3	

Note 1: F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals $-55^\circ C$), then testing immediately without allowing for the junction temperature to stabilize due to heat dissipation after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

Note 2: Screen tested 100% on each device at $-55^\circ C$, $+25^\circ C$, and $+125^\circ C$, Subgroups 1, 2, 3, 7, and 8.

Note 3: Sample tested (Method 5005, Table I) on each manufactured lot at $-55^\circ C$, $+25^\circ C$, and $+125^\circ C$, Subgroups A1, 2, 3, 7, and 8.

Note 4: Guaranteed by applying specified input condition and testing V_{OH}/V_{OL} .

Military Version—Preliminary (Continued)**Ceramic Dual-In-Line Package AC Electrical Characteristics** $V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -55^\circ C$		$T_C = +25^\circ C$		$T_C + 125^\circ C$		Units	Conditions	Notes
		Min	Max	Min	Max	Min	Max			
t _{PLH} t _{PHL}	Propagation Delay Dn to Output	0.30	2.60	0.50	2.40	0.50	2.70	ns	Figures 1, 2	1, 2, 3, 5
t _{PZH} t _{PHZ}	Propagation Delay \overline{OEN} to Output	1.20	5.00	1.40	4.20	1.20	4.30	ns	Figures 1, 2	1, 2, 3, 5
t _{TLH} t _{THL}	Transition Time 20% to 80%, 80% to 20%	0.40	2.50	0.40	2.40	0.40	2.70	ns	Figures 1, 2	4

Cerpak AC Electrical Characteristics $V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -55^\circ C$		$T_C = +25^\circ C$		$T_C + 125^\circ C$		Units	Conditions	Notes
		Min	Max	Min	Max	Min	Max			
t _{PLH} t _{PHL}	Propagation Delay Dn to Output	0.30	2.60	0.50	2.40	0.50	2.70	ns	Figures 1, 2	1, 2, 3, 5
t _{PZH} t _{PHZ}	Propagation Delay \overline{OEN} to Output	1.20	5.00	1.40	4.20	1.20	4.30	ns	Figures 1, 2	1, 2, 3, 5
t _{TLH} t _{THL}	Transition Time 20% to 80%, 80% to 20%	0.40	2.50	0.40	2.40	0.40	2.70	ns	Figures 1, 2	4

Note 1: F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals $-55^\circ C$), then testing immediately after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

Note 2: Screen tested 100% on each device at $+25^\circ C$ temperature only, Subgroup A9.

Note 3: Sample tested (Method 5005, Table I) on each manufactured lot at $+25^\circ C$, Subgroup A9, and at $+125^\circ C$ and $-55^\circ C$ temperatures, Subgroups A10 and A11.

Note 4: Not tested at $+25^\circ C$, $+125^\circ C$, and $-55^\circ C$ temperature (design characterization data).

Note 5: The propagation delay specified is for single output switching. Delays may vary up to 300 ps with multiple outputs switching.

Test Circuitry

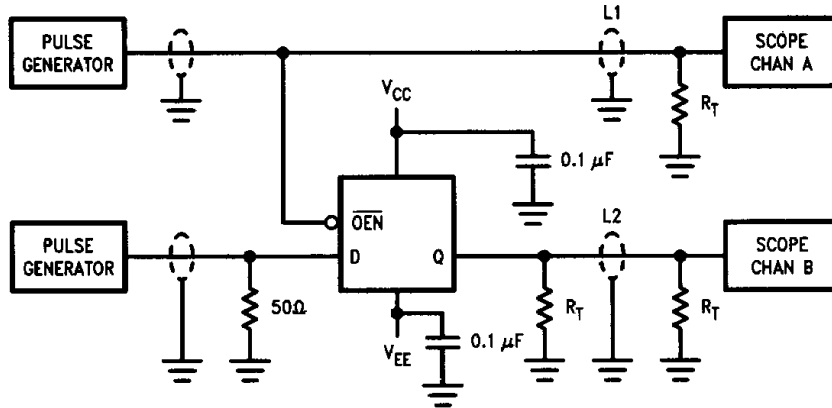


FIGURE 1. AC Test Circuit

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Notes:

- $V_{CC}, V_{CCA} = +2V, V_{EE} = -2.5V$
- L1 and L2 = equal length 50Ω impedance lines
- $R_T = 50\Omega$ terminator internal to scope
- Decoupling $0.1 \mu F$ from GND to V_{CC} and V_{EE}
- All unused outputs are loaded with 50Ω to GND
- $C_L =$ Fixture and stray capacitance $\leq 3 pF$

Switching Waveforms

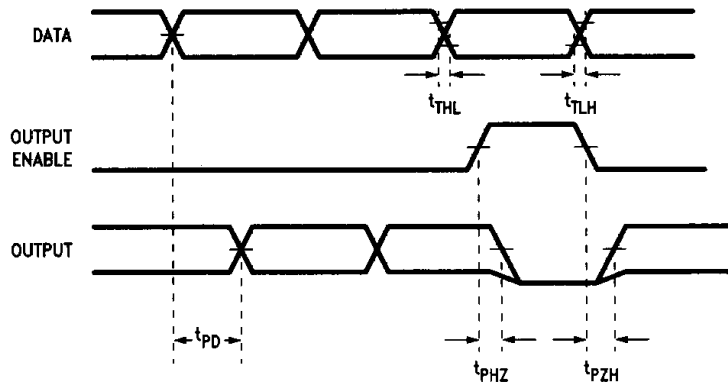


FIGURE 2. Propagation Delay, Cut-Off and Transition Times

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